# FemtoClock® Crystal-to-HCSL Clock Generator

DATA SHEET

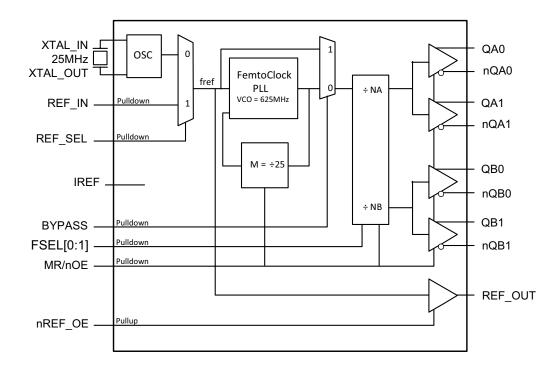
# **General Description**

The ICS841664I is an optimized sRIO clock generator and a member of the family of high-performance clock solutions from IDT. The device uses a 25MHz parallel crystal to generate 125MHz and 156.25MHz clock signals, replacing solution requiring multiple oscillator and fanout buffer solutions. The device has excellent phase jitter (<1ps RMS) suitable to clock components requiring precise and low-jitter sRIO clock signals. Designed for telecom, networking and industrial application, the ICS841664I can also drive the high-speed sRIO SerDes clock inputs of communication processors, DSPs, switches and bridges.

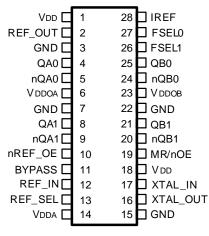
#### **Features**

- Four differential HCSL clock outputs: configurable for sRIO (125MHz or 156.25MHz) clock signals One REF\_OUT LVCMOS/LVTTL clock output
- Selectable crystal oscillator interface, 25MHz, 18pF parallel resonant crystal or LVCMOS/LVTTL single-ended reference clock input or LVCMOS/LVTTL single-ended input
- Supports the following output frequencies: 125MHz or 156.25MHz
- VCO: 625MHz
- Supports PLL bypass and output enable functions
- RMS phase jitter, using a 25MHz crystal (1.875MHz 20MHz): 0.45ps (typical) @ 125MHz
- Full 3.3V power supply mode
- -40°C to 85°C ambient operating temperature
- Lead-free (RoHS 6) packaging

# **Block Diagram**



## Pin Assignment



ICS841664I 28-Lead TSSOP 6.1mm x 9.7mm x 0.925mm package body G Package **Top View** 

# Pin Description and Pin Characteristic Tables

**Table 1. Pin Descriptions** 

Number	Name	T	уре	Description
1, 18	$V_{DD}$	Power		Core supply pins.
2	REF_OUT	Output		LVCMOS/LVTTL reference frequency clock output.
3, 7, 15, 22	GND	Power		Power supply ground.
4, 5, 8, 9	QA0, nQA0 QA1, nQA1	Output		Differential Bank A output pairs. HCSL interface levels.
6	$V_{DDOA}$	Power		Output supply pin for Bank A outputs.
10	nREF_OE	Input	Pullup	Active low REF_OUT enable/disable. See Table 3E. LVCMOS/LVTTL interface levels.
11	BYPASS	Input	Pulldown	Selects PLL/PLL bypass mode. See Table 3C. LVCMOS/LVTTL interface levels.
12	REF_IN	Input	Pulldown	LVCMOS/LVTTL reference clock input.
13	REF_SEL	Input	Pulldown	Reference select, Selects the input reference source. See Table 3B. LVCMOS/LVTTL interface levels
14	$V_{DDA}$	Power		Analog supply pin.
16, 17	XTAL_OUT, XTAL_IN	Input		Parallel resonant crystal interface. XTAL_OUT is the output, XTAL_IN is the input.
19	MR/nOE	Input	Pulldown	Active HIGH master reset. Active LOW output enable. When logic HIGH, the internal dividers are reset and the outputs are in high impedance. When logic LOW, the internal dividers and the outputs are enabled. See Table 3D. LVCMOS/LVTTL interface levels.
20, 21, 24, 25	nQB1, QB1 nQB0, QB0	Output		Differential Bank B output pairs. HCSL interface levels.
23	$V_{DDOB}$	Power		Output supply pin for Bank B outputs.
26, 27	FSEL1, FSEL0	Input	Pulldown	Output frequency select pins. LVCMOS/LVTTL interface levels.
28	IREF	Output		HCSL current reference resistor output. A fixed precision resistor (475 $\Omega$ ) form this pin to ground provides a reference current used for differential current-mode QX[0:1], nQX[0:1] clock outputs.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

**Table 2. Pin Characteristics** 

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
C <sub>IN</sub>	Input Capacitance				4		pF
C <sub>PD</sub>	Power Dissipation Capacitance		V <sub>DD</sub> = 3.465V		4		pF
R <sub>PULLUP</sub>	Input Pullup Resistor				51		kΩ
R <sub>PULLDOWN</sub>	Input Pulldown Resistor				51		kΩ
R <sub>OUT</sub>	Output Impedance	REF_OUT	V <sub>DD</sub> = 3.465V		20		Ω

## **Function Tables**

Table 3A. NA, NB FSELx Function Table ( $f_{ref} = 25MHz$ )

	Inputs		Outputs Frequency Settings		
FSEL1 FSEL0 M		QA[0:1], nQA[0:1]	QB[0:1], nQB[0:1]		
0	0	25	VCO/5 (125MHz)	VCO/5 (125MHz)	
0	1	25	VCO/5 (125MHz)	VCO/4 (156.25MHz)	
1	0	25	VCO/5 (125MHz)	QB0:1 = L, nQB0:1 = H	
1	1	25	VCO/4 (156.25MHz)	VCO/4 (156.25MHz)	

#### Table 3B. REF\_SEL Function Table

Input				
REF_SEL Input Reference				
0	XTAL			
1 REF_IN				

#### Table 3C. BYPASS Function Table

Input				
BYPASS PLL Configuration NOTE 1				
0	PLL enabled			
1	PLL bypassed (QA, QB = fref/Nx, x = A or B)			

NOTE 1: Asynchronous control.

#### Table 3D. MR/nOE Function Table

Input				
MR/nOE	Function NOTE 1			
0	Outputs enabled			
1	Internal dividers reset, outputs disabled (High impedance)			

NOTE 1: Asynchronous control.

#### Table 3E. nREF\_OE Function Table

Input				
nREF_OE Function NOTE 1				
0	REF_OUT enabled			
1	REF_OUT disabled (high impedance)			

NOTE 1: Asynchronous control.

## **Absolute Maximum Ratings**

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V <sub>DD</sub>	4.6V
Inputs, V <sub>I</sub> XTAL_IN Other Inputs	0V to V <sub>DD</sub> -0.5V to V <sub>DD</sub> + 0.5V
Outputs,I <sub>O</sub> Continuous Current REF_OUT Surge Current REF_OUT	± 15mA ± 30mA
Package Thermal Impedance, $\theta_{JA}$	64.5°C/W (0 mps)
Storage Temperature, T <sub>STG</sub>	-65°C to 150°C

#### **DC Electrical Characteristics**

Table 4A. Power Supply DC Characteristics,  $V_{DD} = V_{DDOA} = V_{DDOB} = 3.3V \pm 5\%$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$ 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{DD}$	Core Supply Voltage		3.135	3.3	3.465	V
$V_{DDA}$	Analog Supply Voltage		V <sub>DD</sub> – 0.20	3.3	3.465	V
V <sub>DDOA,</sub> V <sub>DDOB</sub>	Output Supply Voltage		3.135	3.3	3.465	V
I <sub>DD</sub>	Power Supply Current	No Load			80	mA
I <sub>DDA</sub>	Analog Supply Current	No Load			20	mA
I <sub>DDOA</sub> , I <sub>DDOB</sub>	Output Supply Current	No Load, $R_{REF}$ = 475 $\Omega$ $\pm$ 1%			5	mA

Table 4B. LVCMOS/LVTTL DC Characteristics,  $V_{DD} = 3.3V \pm 5\%$ ,  $T_A = -40$ °C to 85°C

Symbol	Parameter Input High Voltage		Test Conditions	Minimum	Typical	Maximum	Units
V <sub>IH</sub>				2		V <sub>DD</sub> + 0.3	V
V <sub>IL</sub>	Input Low Voltage			-0.3		0.8	V
I <sub>IH</sub>	Input High Current	REF_IN, REF_SEL, BYPASS, MR/nOE, FSEL0, FSEL1	V <sub>DD</sub> = V <sub>IN</sub> = 3.465V			150	μA
		nREF_OE	$V_{DD} = V_{IN} = 3.465V$			5	μΑ
I <sub>IL</sub>	Input Low Current	REF_IN, REF_SEL, BYPASS, MR/nOE, FSEL0, FSEL1	V <sub>DD</sub> = 3.465V, V <sub>IN</sub> = 0V	-5			μA
		nREF_OE	$V_{DD} = 3.465V, V_{IN} = 0V$	-150			μA
V <sub>OH</sub>	Output High Voltage; NOTE 1	REF_OUT	V <sub>DD</sub> = 3.465V	2.6			V
V <sub>OL</sub>	Output Low Voltage; NOTE 1	REF_OUT	V <sub>DD</sub> = 3.465V			0.5	V

NOTE 1: Outputs termination with  $50\Omega$  to  $V_{DD}$  /2. See Parameter Measurement Information Section, Output Load Test Circuit diagram.

**Table 5. Crystal Characteristics** 

Parameter	Test Conditions	Minimum	Typical	Maximum	Units
Mode of Oscillation			Fundamenta		
Frequency			25		MHz
Equivalent Series Resistance (ESR)				50	Ω
Shunt Capacitance				7	pF

NOTE: Characterized using an 18pF parallel resonant crystal.

# **AC Electrical Characteristics**

Table 6A. LVCMOS AC Characteristics,  $V_{DD}=3.3V\pm5\%,\,T_{A}=-40^{\circ}C$  to  $85^{\circ}C$ 

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
f <sub>OUT</sub>	Output Frequency RE	EF_OUT			25		MHz
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time		20% to 80%	1.5		2.2	ns
odc	Output Duty Cycle			47		53	%

Table 6B. HCSL AC Characteristics,  $V_{DD} = V_{DDOA} = V_{DDOB} = 3.3V \pm 5\%$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$ 

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
f	Output Frequency		VCO/5		125		MHz
fout			VCO/4		156.25		MHz
tjit(∅)	RMS Phase Jitter (Random); NOTE 1		125MHz, Integration Range: 1.875MHz - 20MHz		0.45	0.55	ps
			156.25MHz, Integration Range: 1.875MHz - 20MHz		0.41	0.54	ps
tjit(cc)	Cycle-to-Cycle Jitter; NC	OTE 3				60	ps
tsk(o)	Output Skew; NOTE 2, 3	QAx, nQAx, QBx, nQBx				140	ps
tL	PLL Lock Time					100	ms
$V_{HIGH}$	Voltage High			650	700	950	mV
$V_{LOW}$	Voltage Low			-150		150	mV
V <sub>OVS</sub>	Max. Voltage, Overshoot					0.3	V
V <sub>UDS</sub>	Min. Voltage, Undershoot			-0.3			V
$V_{RB}$	Ringback Voltage					0.2	V
V <sub>CROSS</sub>	Absolute Crossing Voltage			200		550	mV
$\Delta V_{ ext{CROSS}}$	Total Variation of V <sub>CROSS</sub> over all edges					160	mV
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time	QAx, nQAx, QBx, nQBx	measured between 0.175V to 0.525V	100		700	ps
$\Delta t_R / \Delta t_F$	Rise/Fall Time Variation					125	ps
odc	Output Duty Cycle	QAx, nQAx, QBx, nQBx		47		53	%

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE: All measurements are taken at 125MHz and 156.25MHz.

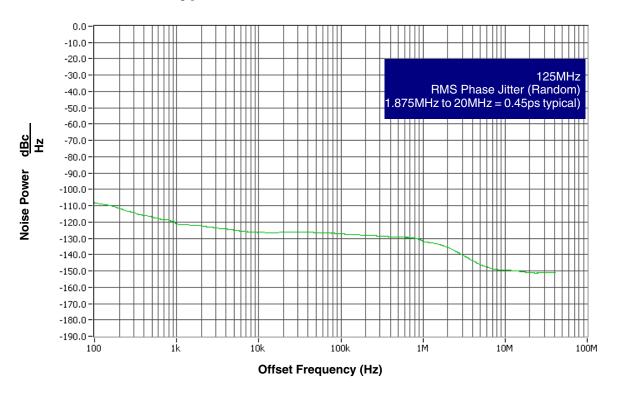
NOTE 1: Please refer to the Phase Noise Plot.

NOTE 2: Defined as skew between outputs at the same supply voltage and with equal load conditions.

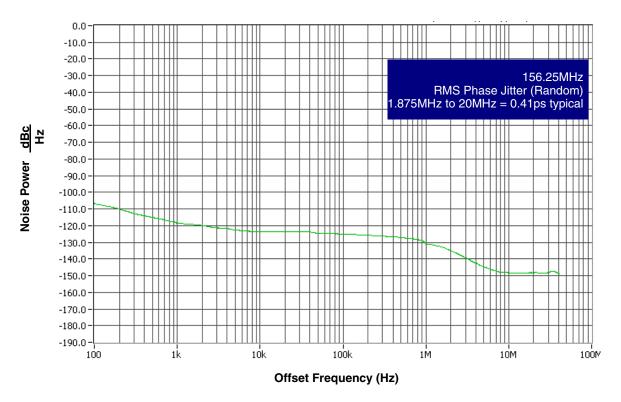
Measured at the differential cross points.

NOTE 3: This parameter is defined in accordance with JEDEC Standard 65.

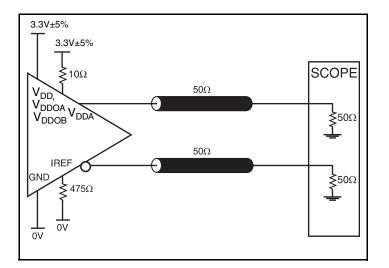
# Typical Phase Noise at 125MHz At 3.3V

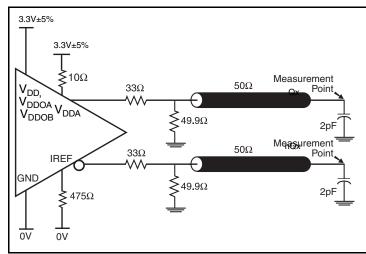


# Typical Phase Noise at 156.25MHz At 3.3V



#### **Parameter Measurement Information**

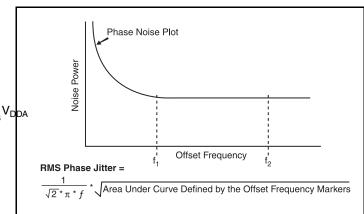




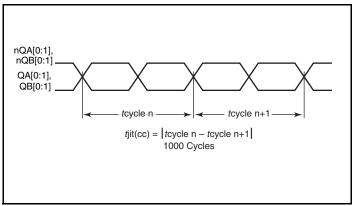
3.3V HCSL Output Load Test Circuit

1.65V±5%  $V_{DD}$   $V_{DDA}$   $Z = 50\Omega$   $Q_{X}$ SCOPE  $V_{DD, V_{DDOA}}$   $V_{DDOA}$   $V_{DDOB}$   $V_{DDOB}$ 

3.3V HCSL Output Load Test Circuit

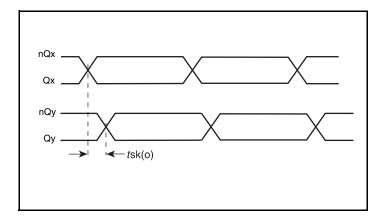


3.3V LVCMOS Output Load Test Circuit



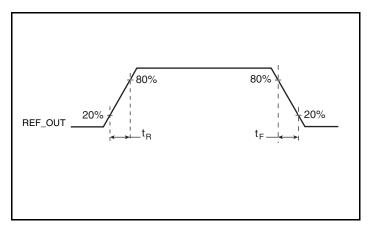
Cycle-to-Cycle Jitter

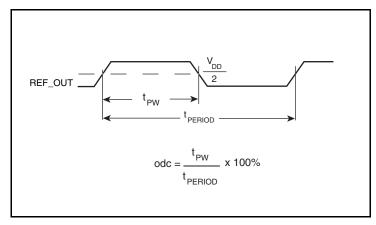
**RMS Phase Jitter** 



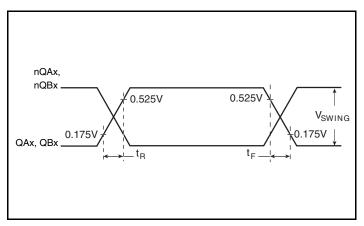
**HCSL Output Skew** 

# **Parameter Measurement Information, continued**

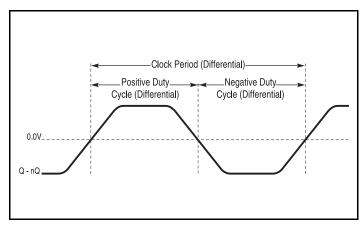




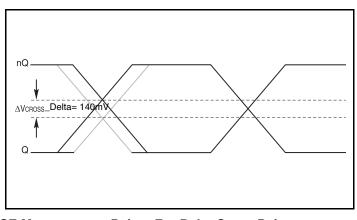
LVCMOS Output Rise/Fall Time



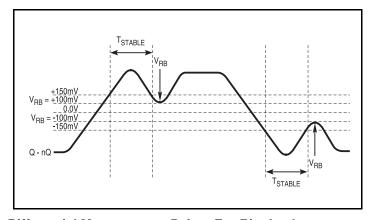
LVCMOS Output Duty Cycle/Pulse Width/Period



**Differential Measurement Points For Rise/Fall Time** 



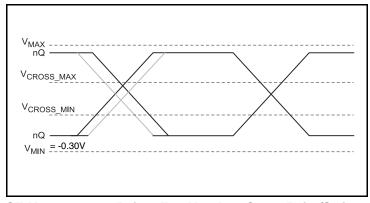
**Differential Measurement Points For Duty Cycle/Period** 



**SE Measurement Points For Delta Cross Point** 

**Differential Measurement Points For Ringback** 

### **Parameter Measurement Information, continued**



SE Measurement Points For Absolute Cross Point/Swing

## **Applications Information**

#### **Recommendations for Unused Input and Output Pins**

#### Inputs:

#### **Crystal Inputs**

For applications not requiring the use of the crystal oscillator input, both XTAL\_IN and XTAL\_OUT can be left floating. Though not required, but for additional protection, a  $1k\Omega$  resistor can be tied from XTAL\_IN to ground.

#### **REF\_CLK Input**

For applications not requiring the use of the reference clock, it can be left floating. Though not required, but for additional protection, a  $1 k\Omega$  resistor can be tied from the REF\_CLK to ground.

#### **LVCMOS Control Pins**

All control pins have internal pullups and pulldowns; additional resistance is not required but can be added for additional protection. A  $1k\Omega$  resistor can be used.

#### **Outputs:**

#### **HCSL Outputs**

All unused HCSL outputs can be left floating. We recommend that there is no trace attached. Both sides of the differential output pair should either be left floating or terminated.

#### **LVCMOS Outputs**

The unused LVCMOS output can be left floating. There should be no trace attached.

#### **Schematic Layout**

Figure 1 shows an example of ICS841664I application schematic. In this example, the device is operated at  $V_{DD} = V_{DDA} = V_{DDOA} = V_{DDOB} = 3.3V$ . The 18pF parallel resonant 25MHz crystal is used. The load capacitance C1 = 27pF and C2 = 27pF are recommended for frequency accuracy. Depending on the parasitic of the printed circuit board layout, these values might require a slight adjustment to optimize the frequency accuracy. Crystals with other load capacitance specifications can be used. This will require

adjusting C1 and C2. For this device, the crystal load capacitors are required for proper operation.

As with any high speed analog circuitry, the power supply pins are vulnerable to random noise. To achieve optimum jitter performance, power supply isolation is required. The ICS841664I provides separate power supplies to isolate any high switching noise from coupling into the internal PLL.

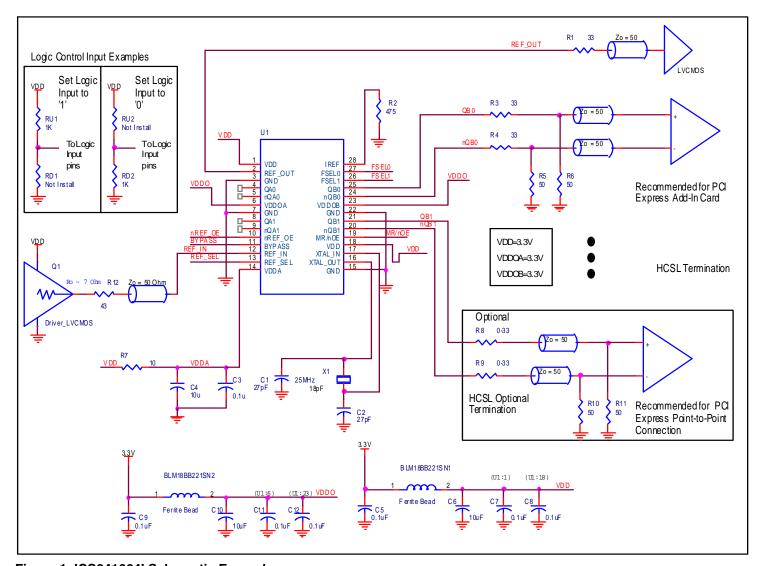


Figure 1. ICS841664I Schematic Example

In order to achieve the best possible filtering, it is recommended that the placement of the filter components be on the device side of the PCB as close to the power pins as possible. If space is limited, the 0.1  $\mu F$  capacitor in each power pin filter should be placed on the device side of the PCB and the other components can be placed on the opposite side.

Power supply filter recommendations are a general guideline to be used for reducing external noise from coupling into the devices. The filter performance is designed for wide range of noise frequency. This low-pass filter starts to attenuate noise at approximately 10kHz. If a specific frequency noise component with high amplitude interference

is known, such as switching power supplies frequencies, it is recommended that component values be adjusted and if required, additional filtering be added. Additionally general design practice for power plane voltage stability suggests adding bulk capacitances in the general area of all devices.

The schematic example focuses on functional connections and is not configuration specific. Refer to the pin description and functional tables in the datasheet to ensure the logic control inputs are properly set.

#### **Overdriving the XTAL Interface**

The XTAL\_IN input can be overdriven by an LVCMOS driver or by one side of a differential driver through an AC coupling capacitor. The XTAL\_OUT pin can be left floating. The amplitude of the input signal should be between 500mV and 1.8V and the slew rate should not be less than 0.2V/nS. For 3.3V LVCMOS inputs, the amplitude must be reduced from full swing to at least half the swing in order to prevent signal interference with the power rail and to reduce internal noise. *Figure 2A* shows an example of the interface diagram for a high speed 3.3V LVCMOS driver. This configuration requires that the sum of the output impedance of the driver (Ro) and the series resistance (Rs) equals the transmission line impedance. In addition, matched termination at the crystal input will attenuate the signal in half. This

can be done in one of two ways. First, R1 and R2 in parallel should equal the transmission line impedance. For most  $50\Omega$  applications, R1 and R2 can be  $100\Omega$ . This can also be accomplished by removing R1 and changing R2 to  $50\Omega$ . The values of the resistors can be increased to reduce the loading for a slower and weaker LVCMOS driver. Figure 2B shows an example of the interface diagram for an LVPECL driver. This is a standard LVPECL termination with one side of the driver feeding the XTAL\_IN input. It is recommended that all components in the schematics be placed in the layout. Though some components might not be used, they can be utilized for debugging purposes. The datasheet specifications are characterized and quaranteed by using a quartz crystal as the input.

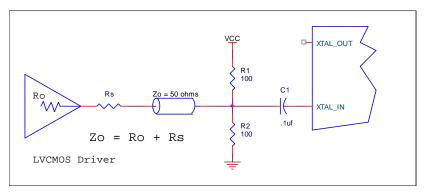


Figure 2A. General Diagram for LVCMOS Driver to XTAL Input Interface

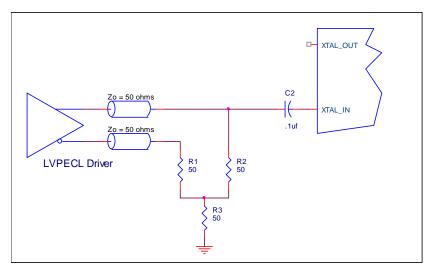


Figure 2B. General Diagram for LVPECL Driver to XTAL Input Interface

# **Applications Information, continued**

#### **Recommended Termination**

Figure 3A is the recommended source termination for applications where the driver and receiver will be on a separate PCBs. This termination is the standard for PCI Express<sup>TM</sup> HCSL output types.

All traces should be  $50\Omega$  impedance single-ended or  $100\Omega$  differential.

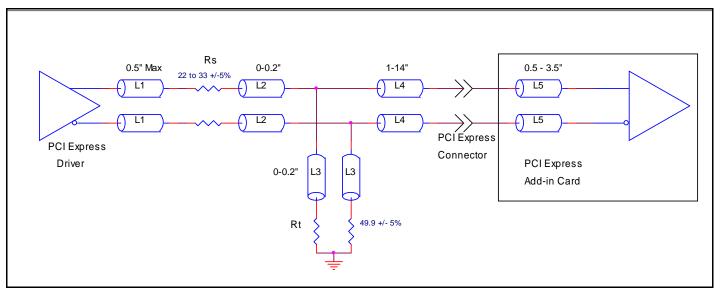


Figure 3A. Recommended Source Termination (where the driver and receiver will be on separate PCBs)

Figure 3B is the recommended termination for applications where a point-to-point connection can be used. A point-to-point connection contains both the driver and the receiver on the same PCB. With a matched termination at the receiver, transmission-line reflections will

be minimized. In addition, a series resistor (Rs) at the driver offers flexibility and can help dampen unwanted reflections. The optional resistor can range from  $0\Omega$  to  $33\Omega$ . All traces should be  $50\Omega$  impedance single-ended or  $100\Omega$  differential.

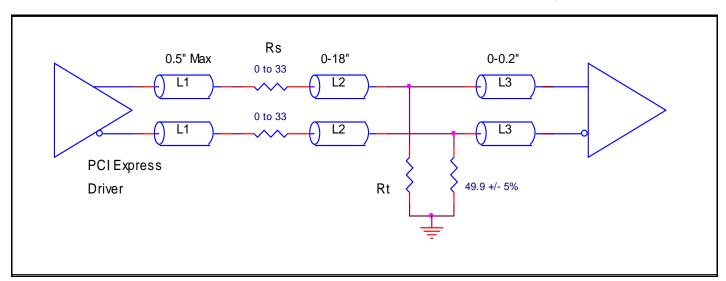


Figure 3B. Recommended Termination (where a point-to-point connection can be used)

#### **Power Considerations**

This section provides information on power dissipation and junction temperature for the ICS841664I. Equations and example calculations are also provided.

#### 1. Power Dissipation.

The total power dissipation for the ICS841664I is the total power minus the analog power plus the power dissipated into the load. The following is the power dissipation for  $V_{DD} = 3.3V + 5\% = 3.465V$ , which gives worst case results.

#### **Core and HCSL Output Power Dissipation**

- Power (core)<sub>MAX</sub> =  $V_{DD\_MAX}$  \* ( $I_{DD\_MAX}$  +  $I_{DDA\_MAX}$ ) = 3.465V \* (80mA + 20mA) = **346.5mW**
- Power (outputs)<sub>MAX</sub> = 44.5mW/Loaded Output pair

If all outputs are loaded, the total power is 4 \* 44.5mW = 178mW

#### **LVCMOS Driver Power Dissipation**

Dynamic Power Dissipation at 25MHz

Power (25MHz) =  $C_{PD}$  \* Frequency \*  $(V_{DD})^2$  = 4pF \* 25MHz \*  $(3.465V)^2$  = **1.20mW per output** 

#### **Total Power Dissipation**

- Total Power
  - = Power (core) + Power (Outputs) + Total Power (25MHz)
  - = 346.5 mW + 178 mW + 1.2 mW
  - = 525.7mW

#### 2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad directly affects the reliability of the device. The maximum recommended junction temperature is 125°C. Limiting the internal transistor junction temperature, Tj, to 125°C ensures that the bond wire and bond pad temperature remains below 125°C.

The equation for Tj is as follows: Tj =  $\theta_{JA}$  \* Pd\_total + T<sub>A</sub>

Tj = Junction Temperature

 $\theta_{\mathsf{JA}}$  = Junction-to-Ambient Thermal Resistance

Pd\_total = Total Device Power Dissipation (example calculation is in section 1 above)

T<sub>A</sub> = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{JA}$  must be used. Assuming no air flow and a multi-layer board, the appropriate value is 64.5°C/W per Table 7 below.

Therefore, Tj for an ambient temperature of 85°C with all outputs switching is:

 $85^{\circ}\text{C} + 0.526\text{W} * 64.3^{\circ}\text{C/W} = 118.9^{\circ}\text{C}$ . This is below the limit of  $125^{\circ}\text{C}$ .

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (multi-layer).

#### Table 7. Thermal Resistance $\theta_{JA}$ for 28 Lead TSSOP, Forced Convection

$\theta_{JA}$ by Velocity				
Meters per Second	0	1	2.5	
Multi-Layer PCB, JEDEC Standard Test Boards	64.5°C/W	60.4°C/W	58.5°C/W	

#### 3. Calculations and Equations.

The purpose of this section is to calculate power dissipation on the IC per HCSL output pair.

HCSL output driver circuit and termination are shown in Figure 4.

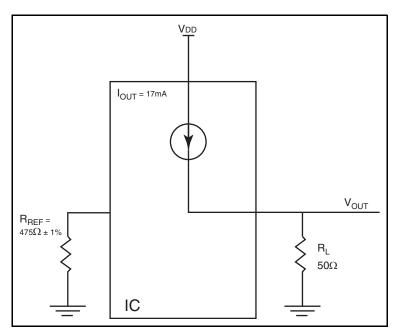


Figure 4. HCSL Driver Circuit and Termination

HCSL is a current steering output which sources a maximum of 17mA of current per output. To calculate worst case on-chip power dissipation, use the following equations which assume a  $50\Omega$  load to ground.

The highest power dissipation occurs when  $V_{DD-MAX}$ .

Power = 
$$(V_{DD\_MAX} - V_{OUT}) * I_{OUT}$$
  
since  $V_{OUT} = I_{OUT} * R_L$   
Power =  $(V_{DD\_MAX} - I_{OUT} * R_L) * I_{OUT}$   
=  $(3.465V - 17mA * 50\Omega) * 17mA$ 

Total Power Dissipation per output pair = 44.5mW

# **Reliability Information**

Table 8.  $\theta_{\text{JA}}$  vs. Air Flow Table for a 28 Lead TSSOP

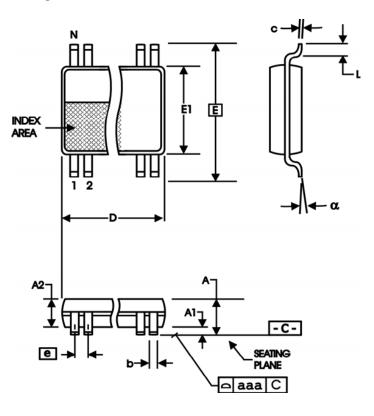
$\theta_{JA}$ by Velocity				
Meters per Second	0	1	2.5	
Multi-Layer PCB, JEDEC Standard Test Boards	64.5°C/W	60.4°C/W	58.5°C/W	

#### **Transistor Count**

The transistor count for ICS841664I is: 2954

# **Package Outline and Package Dimensions**

Package Outline - G Suffix for 28 Lead TSSOP



**Table 9. Package Dimensions** 

All Dimensions in Millimeters				
Symbol	Minimum	Maximum		
N	28			
Α		1.20		
A1	0.05	0.15		
A2	0.80	1.05		
b	0.19	0.30		
С	0.09	0.20		
D	9.60	9.80		
E	8.10 Basic			
E1	6.00	6.20		
е	0.65 Basic			
L	0.45	0.75		
α	0°	8°		
aaa		0.10		

Reference Document: JEDEC Publication 95, MO-153

# **Ordering Information**

# **Table 10. Ordering Information**

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
841664AGILF	ICS841664AGI	28 Lead "Lead-Free" TSSOP	Tube	-40°C to 85°C
841664AGILFT	ICS841664AGI	28 Lead "Lead-Free" TSSOP	Tape & Reel	-40°C to 85°C

# **Revision History Sheet**

Rev	Table	Page	Description of Change	Date
Α	T1 T10	2 18	Pin Description Table - switched pin names for pins 20 through 25. Ordering Information Table - deleted Tape & Reel quantity.	7/15/13

# We've Got Your Timing Solution



6024 Silver Creek Valley Road San Jose, California 95138

Sales

800-345-7015 (inside USA) +408-284-8200 (outside USA) Fax: 408-284-2775

www.IDT.com/go/contactIDT

**Technical Support Sales** 

netcom@idt.com +480-763-2056

DISCLAIMER Integrated Device Technology, Inc. (IDT) and its subsidiaries reserve the right to modify the products and/or specifications described herein at any time and at IDT's sole discretion. All information in this document, including descriptions of product features and performance, is subject to change without notice. Performance specifications and the operating parameters of the described products are determined in the independent state and are not guaranteed to perform the same way when installed in customer products. The information contained herein is provided without representation or warranty of any kind, whether express or implied, including, but not limited to, the suitability of IDT's products for any particular purpose, an implied warranty of merchantability, or non-infringement of the intellectual property rights of others. This document is presented only as a guide and does not convey any license under intellectual property rights of IDT's products.

IDT's products are not intended for use in applications involving extreme environmental conditions or in life support systems or similar devices where the failure or malfunction of an IDT product can be reasonably expected to significantly affect the health or safety of users. Anyone using an IDT product in such a manner does so at their own risk, absent an express, written agreement by IDT.

Integrated Device Technology, IDT and the IDT logo are registered trademarks of IDT. Other trademarks and service marks used herein, including protected names, logos and designs, are the property of IDT or their respective third

Copyright 2013. All rights reserved.